

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS17485	Nov-97	9726 A2	ANAM, K.	DN713702AAC	0.8μ OX/NI (2 MTL)	24 SOIC

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
 Bake, 125°C, 24 Hr
 Moisture Soak, 30°C/60% RH, 144 Hr
 Vapor Phase Reflow, 3 Passes, P-20859

<u>0 Hr</u>	<u>Electrical</u>	<u>Cum %</u>
250/0	237/0	0.0%

Sonoscan
P-20960

Post Vapor Phase

Infant / High Voltage Life 125°C, 7.0 V. P-20961, P-21028	<u>48 Hr</u> 231/0	<u>336 Hr</u> 77/0	<u>1KHr</u>	<u>*Failure Rate</u>
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*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-21029	<u>300 ~</u> 50/0	<u>1K ~</u>	<u>Cum %</u>
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Biased Moisture (HAST) 120°C/85% RH, 5.5 V. P-21030		<u>100 Hr</u> 65/0	<u>Cum %</u> 0.0%
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Autoclave 121°C/100% RH, 2 Atmos P-21031		<u>96 Hr</u> 40/0	<u>Cum %</u> 0.0%
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Failure Mode

Failure Analysis